

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

Sheet 1 of 1

APPLICATION NO.

1514.1030

FIRST NAMED INVENTOR

JI Yong PARK et al.

FILING DATE

December 15, 2003

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	AA						
	AB						
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FOREIGN PATENT DOCUMENTS

	DOCUMENT NO.	DATE	COUNTRY	TRANSLATION YES NO	ABSTRACT
AG					
AH					
Al					

OTHER RE	TRANSL YES	ATION NO		
	AJ	Wang, Mingxiang and Man Wong. "Characterization of an Individual Grain Boundary in Metal-Induced Laterally Crystallized Polycrystalline Silicon Thin-Film Devices." IEEE Transactions on Electron Devices. Vol. 48, No. 8, August 2001, pages 1655-1660.		
	AK	Cho, Hans Set al. "Sequential Lateral Solidification of Ultra-Thin a-Si Films." Mat. Res. Soc. Symp. Proc. Vol. 621, 2001, pages 1-6.		

EXAMINER	DATE CONSIDERED		
much Chler	8/5/06		
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.			

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Sheet 1 of 1
ATTORNEY DOCKET NO. APPLICATION NO.

1514.1030 10/734,162

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me	AG	JP 11-354800	12/1999	JAPAN		Х
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	AK					
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)				
men	АМ	Office Action issued in Chinese Patent Application No. 200310109779.2 on September 2, 2005.	x	

EXAMINER	DATE CONSIDERED			
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